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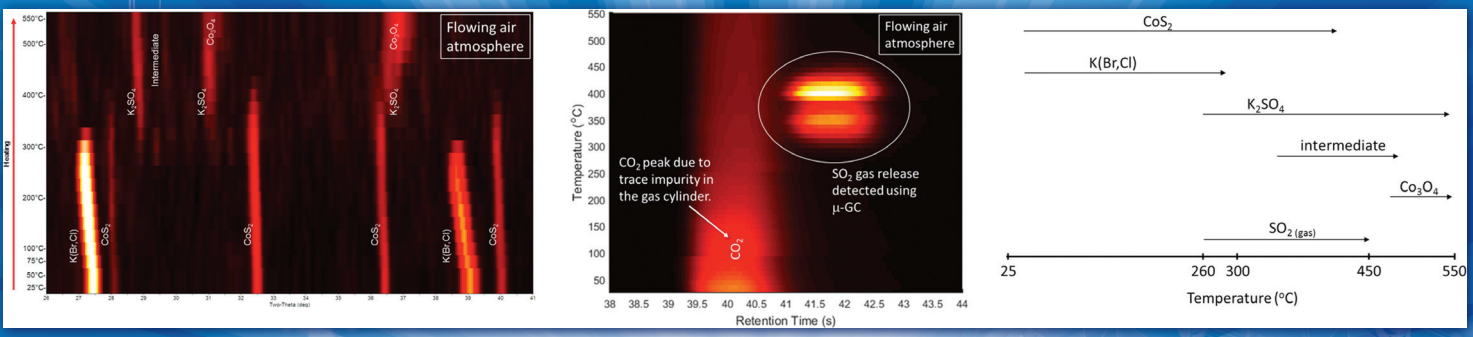

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EDITORIAL

TECHNICAL ARTICLES

NEW DIFFRACTION DATA

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Powder Diffraction

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On the Cover: From Figures 4, 5 and 8 in Technical Article "Monitoring of CoS_2 Reactions Using High Temperature XRD Coupled with Gas Chromatography (GC)": Concurrent Gas Chromatography was coupled with High Temperature X-Ray Diffraction to successfully revealed the reaction sequences of cobalt disulfide cathode materials in air as a function of temperature. Left – HTXRD patterns showing decomposition of the CoS_2 and formation of new phases. Middle – gas chromatography results revealing SO_2 off-gas species between ~260° C and 450° C. Right – the derived reaction sequences. The vertical axis in each plot shows the temperature. (Courtesy: Rodriguez, M. A.; Coker, E. N.; Griego, J. J. M.; Mowry, C. D.; Pimentel, A. S. and Anderson, T. M. of Sandia National Laboratory).

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